

IEC QUALITY ASSESSMENT SYSTEM (IECQ) covering Electronic Components,

Assemblies, Related Materials and Processes For rules and details of the IECQ visit www.iecq.org

## Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 17.0001

CB Certificate No.: 50600164 ITL

Schedule Number: IECQ-L ULTW 17.0001-S Rev No.: 2 Revision Date: 2022/03/31 Page 1 of 2

## **Appendix-1 (50600164 ITL) Schedule of Scope to Certificate of Approval**

Test Items	Standard/Method
I-V Probe station	WI-LQ-0120 Probe station Work Instruction
InGaAs microscope/Optical Beam Induced Resistance Change (OBIRCH)	WI-LQ-0313 Meridian Work Instruction
SAT (Scanning Acoustic Tomography)	WI-LQ-0320 SAT Work Instruction
3D X-ray	WI-LQ-0324 3D X-ray Work Instruction
Secondary Electron Microscope (SEM)	WI-LQ-0302 SEM Work Instruction
Focused Ion Beam (FIB)	WI-LQ-0108 FIB Work Instruction
Electrostatic Discharge (ESD) / Latch-up (Heating by Thermo stream)	HBM: ANSI/ESDA/JEDEC JS-001/JESD22-A114 / AEC-Q100-002 / MIL-STD-883 MM: JED22-A115 / AEC-Q100-003 CDM: ANSI/ESDA/JEDEC JS-002 / JESD22-C101 / AEC-Q100-011 Latch : JESD78 / AEC-Q100-004
High Temperature Operating Life (HTOL)	JESD22-A108
Bias Life Test (BLT)	JESD22-A108
Early Failure Rate (EFR)	JESD22-A108
High Temperature Storage Life (HTSL)	JESD22-A103
Low Temperature Storage Life (LTSL)	JESD22-A108
Highly Accelerated Temperature And Humidity Stress Test (HAST)	JESD22-A110
Unbiased HAST	JESD22-A118
Pressure Cook Test (PCT)	JESD22-A102

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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

IECQ-P Schedule of Scope Rev. 01



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Temperature Cycling Test (TCT)	JESD22-A104
Thermal Shock Test (TST)	JESD22-A106
Precondition	IPC/JEDEC J-STD-020D Level 3, JESD22-A113
Steady State Temperature Humidity Bias Life Test (THB)	JESD22-A101

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Technical Reviewer of DQS:

Date: 3/31/2022

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